

Appl. No.	:	Unassigned	Confirmation No.	Unassigned
First Inventor	:	AZIMANE, Mohamed		
Filed	:	Concurrently		
TC/A.U.	:	Unassigned		
Examiner	:	Unassigned		

Docket No.	:	<b>US040161US2</b>
Customer No.	:	24738

Title:                                      Method for Detecting Resistive-Open Defects In  
Semiconductor Memories

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**PRELIMINARY AMENDMENT**

Sir:

Prior to calculation of the filing fee and examination please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** begin on page 3 of this paper.

**Remarks/Arguments** begin on page 7 of this paper.